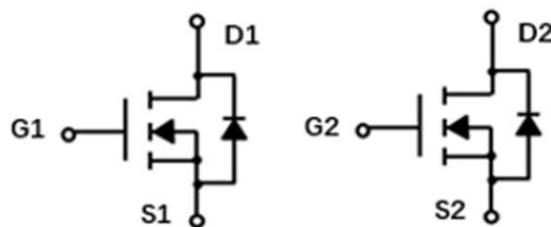
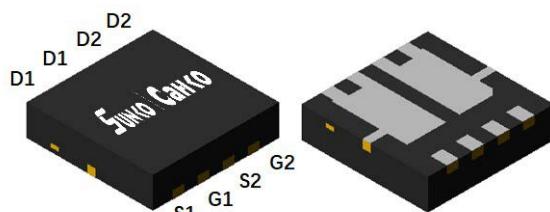


N-Channel Enhancement Mode Field Effect Transistor

DFN3.3X3.3



Product Summary

- V_{DS} 40 V
- I_D 25 A
- $R_{DS(ON)}$ (at $V_{GS} = 10V$) < 19 mohm
- $R_{DS(ON)}$ (at $V_{GS} = 4.5V$) < 25 mohm
- 100% UIS Tested
- 100% ∇V_{DS} Tested

General Description

- Trench Power LV MOSFET technology
- Excellent package for heat dissipation
- High density cell design for low $R_{DS(ON)}$

Applications

- High current load applications
- Load switching
- Hard switched and high frequency circuits
- Uninterruptible power supply

■ Absolute Maximum Ratings ($T_A=25^\circ\text{C}$ unless otherwise noted)

Parameter		Symbol	Limit	Unit
Drain-source Voltage		V_{DS}	40	V
Gate-source Voltage		V_{GS}	± 20	V
Drain Current	$T_c=25^\circ\text{C}$	I_D	25	A
	$T_c=100^\circ\text{C}$		16	
Pulsed Drain Current ^A		I_{DM}	100	A
Single Pulse Avalanche Energy ^B		E_{AS}	70	mJ
Total Power Dissipation	$T_c=25^\circ\text{C}$	P_D	21	W
Thermal Resistance Junction-to-Case		$R_{\theta JC}$	6.0	$^\circ\text{C} / \text{W}$
Junction and Storage Temperature Range		T_J, T_{STG}	-55~+150	$^\circ\text{C}$

■ Ordering Information (Example)

PREFERRED P/N	PACKING CODE	Marking	MINIMUM PACKAGE(pcs)	INNER BOX QUANTITY(pcs)	OUTER CARTON QUANTITY(pcs)	DELIVERY MODE
SCQD25N04A	F1	QD25N04A	5000	10000	100000	13" reel

■ Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
Static Parameter						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	40			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}}=40\text{V}, V_{\text{GS}}=0\text{V}$			1	μA
Gate-Body Leakage Current	I_{GSS}	$V_{\text{GS}}= \pm 20\text{V}, V_{\text{DS}}=0\text{V}$			± 100	nA
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	1.0	1.5	2.5	V
Static Drain-Source On-Resistance	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}}= 10\text{V}, I_{\text{D}}=20\text{A}$		14.5	19	$\text{m}\Omega$
		$V_{\text{GS}}= 4.5\text{V}, I_{\text{D}}=10\text{A}$		18	25	
Diode Forward Voltage	V_{SD}	$I_{\text{S}}=20\text{A}, V_{\text{GS}}=0\text{V}$		0.7	1.2	V
Dynamic Parameters						
Input Capacitance	C_{iss}	$V_{\text{DS}}=20\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHZ}$		917		pF
Output Capacitance	C_{oss}			128		
Reverse Transfer Capacitance	C_{rss}			108		
Switching Parameters						
Total Gate Charge	Q_g	$V_{\text{GS}}=10\text{V}, V_{\text{DS}}=20\text{V}, I_{\text{D}}=20\text{A}$		23.6		nC
Gate-Source Charge	Q_{gs}			4.4		
Gate-Drain Charge	Q_{gd}			6.3		
Reverse Recovery Charge	Q_{rr}	$I_F=20\text{A}, dI/dt=100\text{A/us}$		0.4		ns
Reverse Recovery Time	t_{rr}			7		
Turn-on Delay Time	$t_{D(\text{on})}$			10		
Turn-on Rise Time	t_r	$V_{\text{GS}}=10\text{V}, V_{\text{DD}}=20\text{V}, I_{\text{D}}=2\text{A}, R_{\text{GEN}}=3\Omega$		56		ns
Turn-off Delay Time	$t_{D(\text{off})}$			27		
Turn-off fall Time	t_f			72		

A. Pulse Test: Pulse Width $\leq 300\text{us}$, Duty cycle $\leq 2\%$.B. $R_{\theta JA}$ is the sum of the junction-to-case and case-to-ambient thermal resistance, where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{euc} is guaranteed by design, while $R_{\theta JA}$ is determined by the board design. The maximum rating presented here is based on mounting on a 1 in 2 pad of 2oz copper.

■ Typical Performance Characteristics

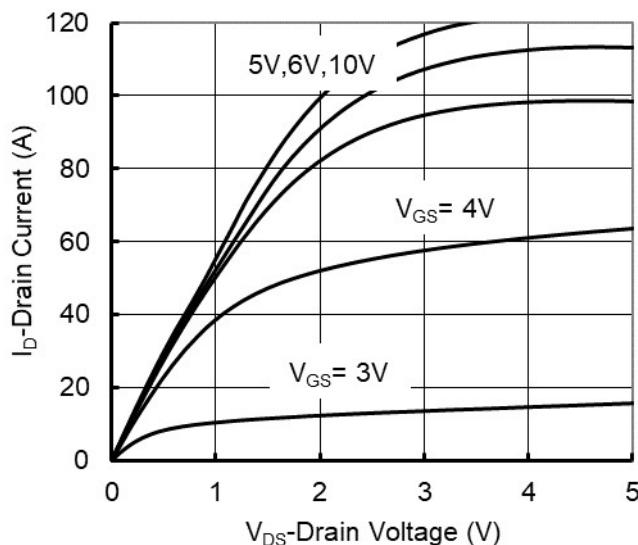


Figure 1. Output Characteristics

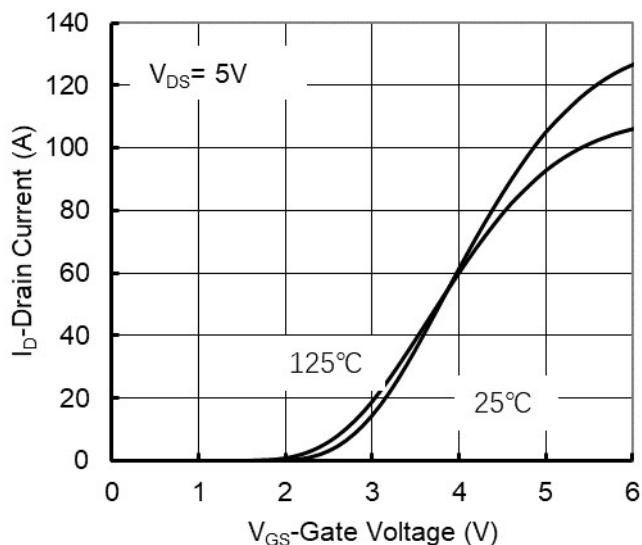


Figure 2. Transfer Characteristics

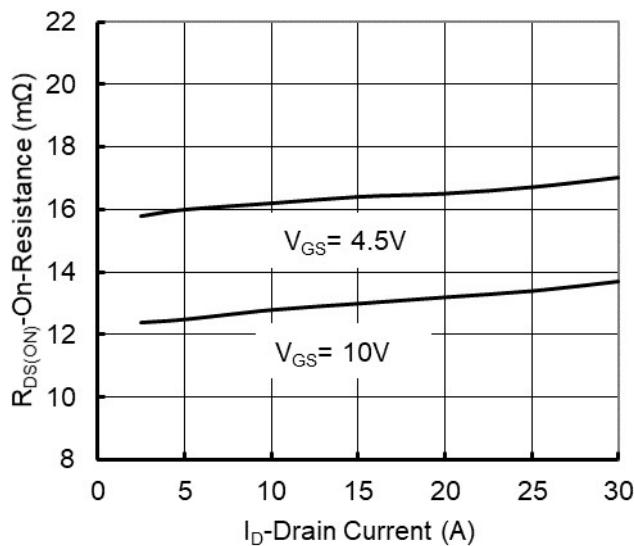


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

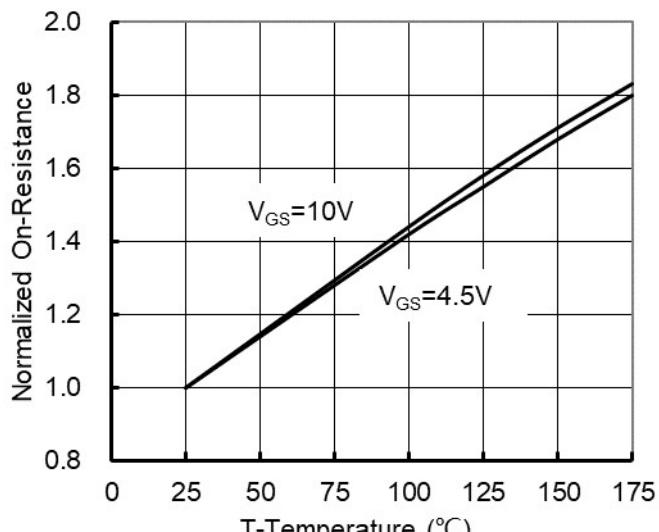


Figure 4. On-Resistance vs. Junction Temperature

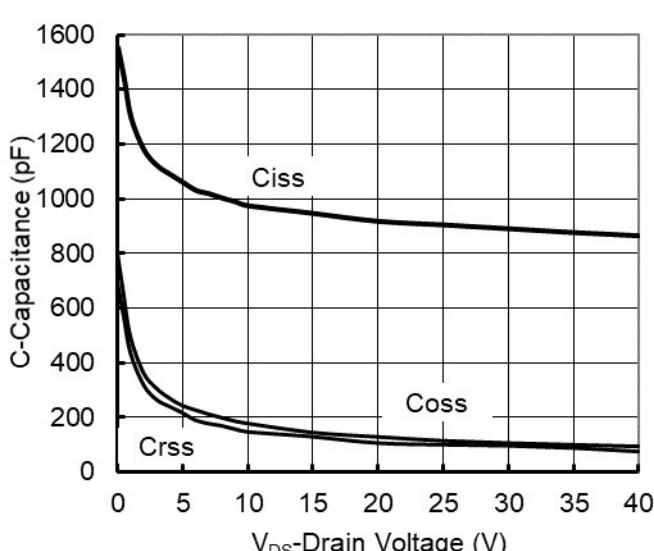


Figure 5. Capacitance Characteristics

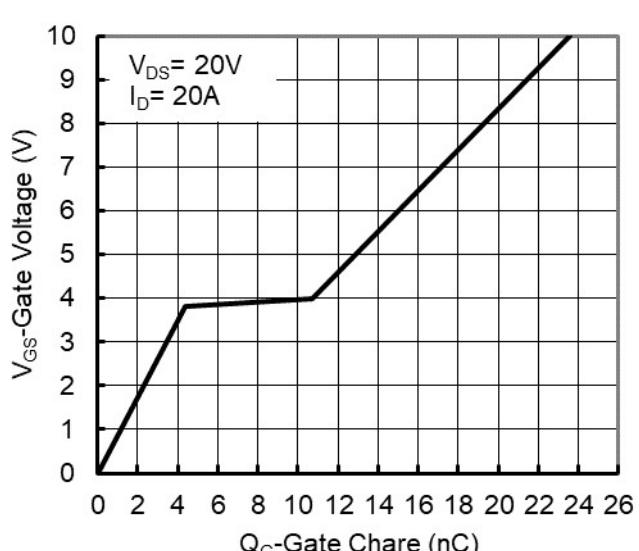
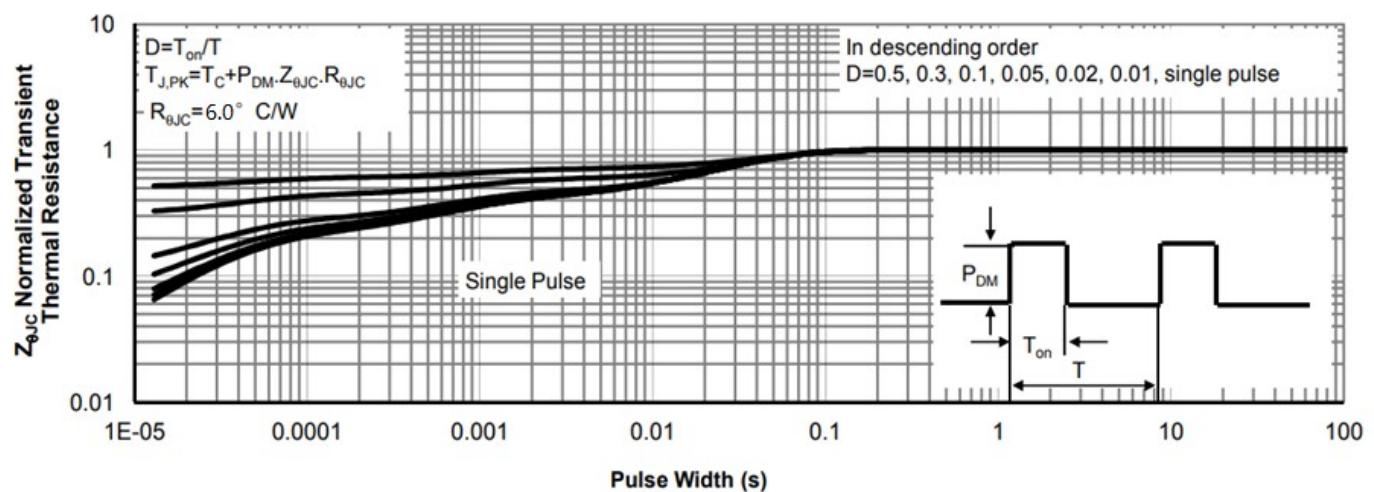
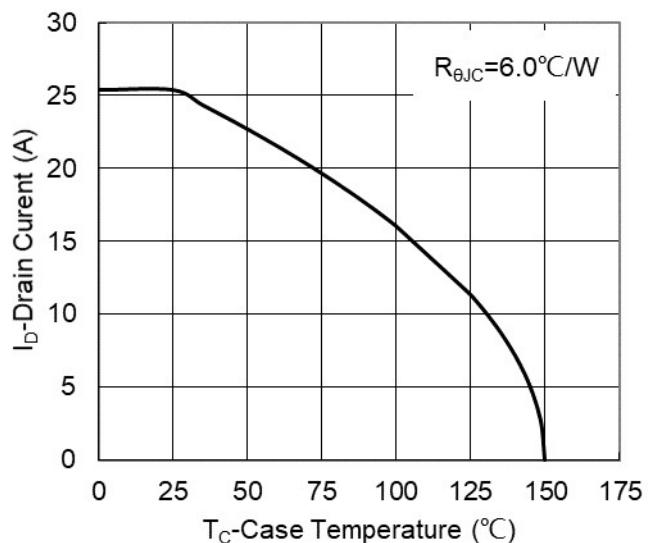
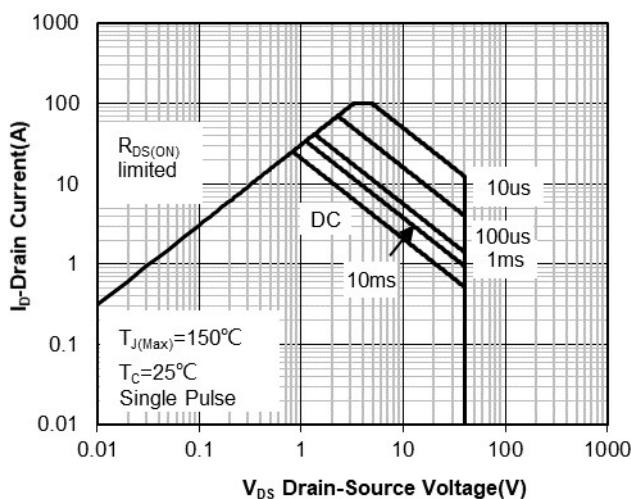
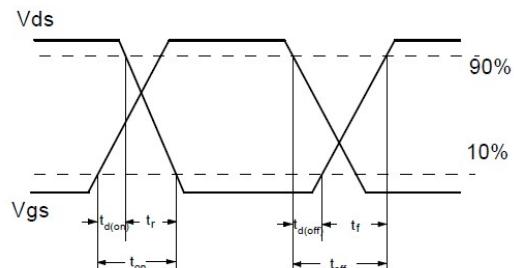
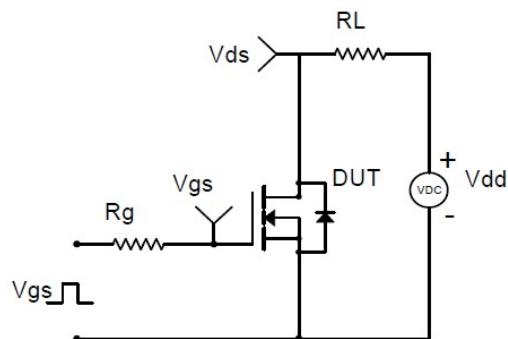
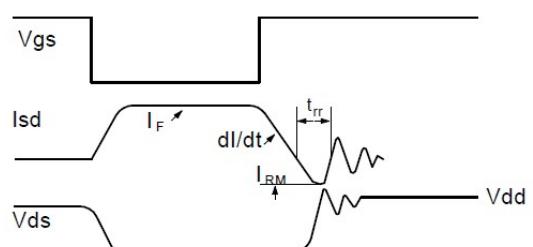
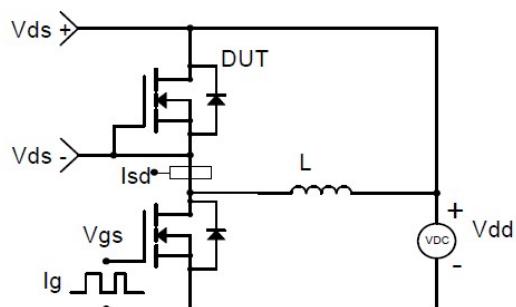


Figure 6. Gate Charge

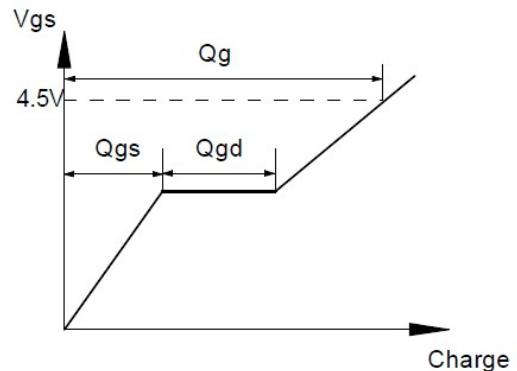
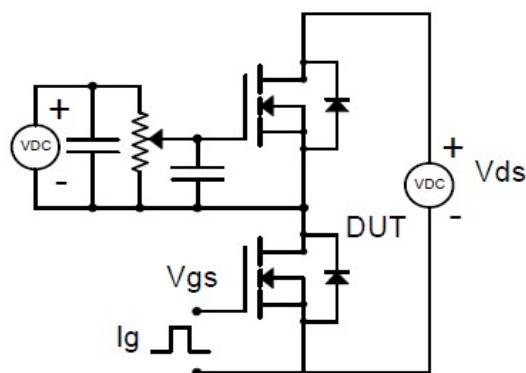




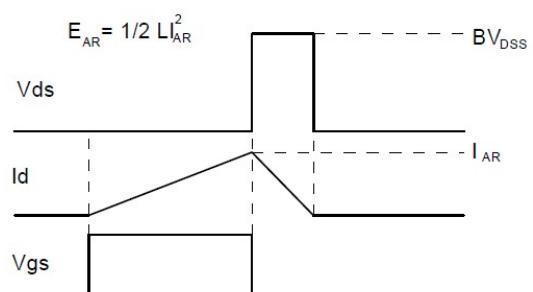
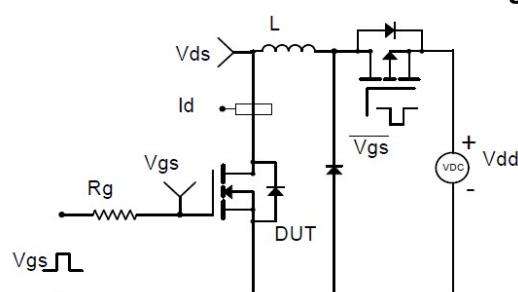
Resistive Switching Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

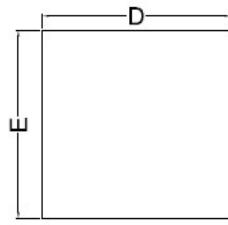


Gate Charge Test Circuit & Waveform

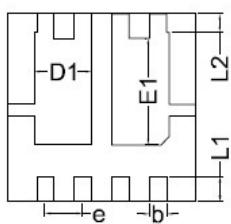


Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

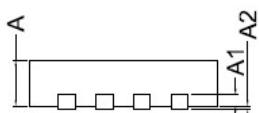
■ DFN3.3x3.3 Package information



Top View
正面视图



Bottom View
背面视图

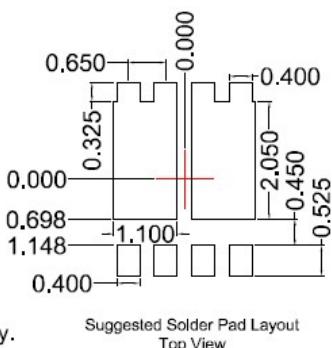


Side View
侧面视图

SYMBOL	MILLIMETER		
	MIN	NOM	MAX
D	3.15	3.25	3.35
E	3.15	3.25	3.35
A	0.70	0.80	0.90
A1		0.20 BSC	
A2			0.10
D1	0.90	1.00	1.10
E1	1.75	1.85	1.95
L1	0.325	0.425	0.525
L2		0.325 BSC	
b	0.20	0.30	0.40
e		0.65 BSC	

Note:

1. Controlling dimension: in millimeters.
 2. General tolerance: ± 0.10 mm.
 3. The pad layout is for reference purposes only.



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